



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/684,909	MOLL ET AL.	
Examiner	Art Unit	
Tanh Q. Nguyen	2182	

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Class	Subclass	Date	Examiner
709	201, 702 205,213-215 217, 218,226 221,248,246 15,17-21	0/04/06	TON
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713	100, 375 cenda	J	6
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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